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NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10057674	01/24/2002	430		1756	BARRECA, N

APPLICANTS: Hwang Jeng; Mak Steve; Lin Tru-Lon; Ying Chentsau; Schaller John;

CONTINUING DATA VERIFIED:

This application is a CON of 09/421,467 10/19/1999 ABN
which is a CIP of 09/251,588 02/17/1999 ABN
and is a CIP of 09/251,826 02/17/1999 PAT 6,323,132
and is a CIP of 09/251,633 02/17/1999 PAT 6,265,318
which is a CIP of 09/006,092 01/13/1998 ABN

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FOREIGN APPLICATIONS VERIFIED:

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>
Foreign priority claimed	<input type="checkbox"/> yes <input checked="" type="checkbox"/> no	ATTORNEY DOCKET NO
35 USC 119 conditions met	<input type="checkbox"/> yes <input checked="" type="checkbox"/> no	AM-2602.C1
Verified and Acknowledged Examiner's initials		
TITLE: Masking methods and etching sequences for patterning electrodes of high density RAM capacitors		

U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G.
Assistant Examiner		DRAWING	
Amount Due		Sheets Drwg.	Figs. Drwg.
Date Paid		Print Fig.	
Primary Examiner		Application Examiner	
<input type="checkbox"/> TERMINAL DISCLAIMER		PREPARED FOR ISSUE	
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